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L3	99	apc same model and wafer	USPAT	OR	OFF	2006/07/04 11:14
L4	1851	film adj stack	USPAT	OR	OFF	2006/07/04 11:14
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IEEE CNF IEEE Conference Proceeding


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 Lagrange, A.; Poupinet, L.;  
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[Photovoltaic Specialists Conference, 2000. Conference Record of the Twenty-Eighth IEEE](#)  
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**Film Stack** Analysis. Measurement. =. Model. **Simulation** ? ... Inline/**in-situ** capable. •

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From this **simulation** we can also infer a source layer thickness of approx 10 Å ... A hole in the middle of this **film stack** provides a line of sight for a ...

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and illumination wavelength,  $\lambda$  ( $\mu\text{m}$ ), from **simulation** as in Figure 2 with lines for 0.18  $\mu\text{m}$  ... libraries require knowledge of the **film stack** properties. ...

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libraries require knowledge of the **film stack** properties. ... **APC simulation**, and process-window RSA to separate correctable systematic cell, lot, ...

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In this approach, a **film stack** is deposited with a single recipe on a PECVD tool where

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